

Appln. No.: 09/775,676  
Amendment Dated: January 11, 2006  
Reply to Final Office Action of November 3, 2005

PRO-128US

**Amendments to the Claims:** This listing of claims will replace all prior versions, and listings, of claims in the application

## Listing of Claims

1. - 10. (Cancelled).

11. (Previously Presented) A method of compensating for a voltage drop of an operational signal passing through an operational signal path, said method comprising the steps of:

contacting a single terminal of an integrated circuit device with a probe group comprising two or more probes;

determining a plurality of path resistances along respective pairs of said two or more probes of said probe group, said single terminal and respective interfaces between said probes and said single terminal;

deriving an operational signal path resistance based on said plurality of path resistances, the deriving step including (a) identifying a constant portion of each of the path resistances and a variable portion of each of the path resistances, and (b) comparing the variable portion of each of the path resistances with one another to derive the operational signal path resistance; and

compensating for said voltage drop in correspondence to said derived operational signal path resistance.

12. (Previously Presented) The method of claim 11, wherein said contacting step is provided by said probe group including a first, a second and a third of said probes, wherein said determining step includes determining a first, a second and a third path resistance corresponding to conductive paths including said first, said second and said third of said probes, and wherein said deriving includes deriving an absolute value of a first, a second and a third variable portion of each of said first path resistance, said second path resistance and said third path resistance.

13. - 17. (Cancelled).

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18. (New) The method of claim 11 wherein the contacting step includes contacting the single terminal with the two or more probes such that the probes are electrically isolated from one another.

19. (New) The method of claim 11 wherein the contacting step includes contacting the single terminal with the two or more probes such that a substantially spherically shaped tip of each of the probes contacts the single terminal.

20. (New) The method of claim 19 further comprising the step of self centering the probe group on the single terminal at least partially via the substantially spherically shaped tips.

21. (New) The method of claim 19 wherein the contacting step includes substantially concurrently contacting the single terminal with each of the two or more probes.

22. (New) The method of claim 11 further comprising the step of establishing a force induced contact between (1) an end of each of the two or more probes opposite the single terminal, and (2) a terminal of a system configured to provide a voltage signal to the two or more probes.

23. (New) The method of claim 11 further comprising the step of establishing a friction based contact between (1) an end of each of the two or more probes opposite the single terminal, and (2) a terminal of a system configured to provide a voltage signal to the two or more probes.

24. (New) The method of claim 11 wherein the deriving step includes identifying the constant portion to include a resistance of (1) each of the two or more probes, and (2) the single terminal.

25. (New) The method of claim 11 wherein the deriving step includes identifying the variable portion to include a resistance of an interface between (1) each of the two or more probes, and (2) the single terminal.

26. (New) The method of claim 25 wherein the deriving step includes identifying the variable portion to also include a resistance of another interface

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between (1) each of the two or more probes, and (2) a terminal of a system configured to provide a voltage signal to the two or more probes.

27. (New) The method of claim 11 wherein the compensating step includes increasing an applied voltage to at least a portion of the two or more probes.

28. (New) The method of claim 11 wherein the contacting step includes contacting the single terminal with the probe group consisting of two probes.

29. (New) The method of claim 11 wherein the contacting step includes contacting the single terminal with the probe group consisting of three probes.

30. (New) The method of claim 11 wherein the contacting step includes contacting the single terminal with the probe group consisting of three probes, and wherein the determining step includes (1) determining a first path resistance along a first and a second of the three probes, (2) determining a second path resistance along the first and a third of the three probes, and (3) determining a third path resistance along of the second and a third of the three probes.

31. (New) The method of claim 11 wherein the contacting step includes contacting the single terminal with the probe group consisting of four probes.

32. (New) The method of claim 11 wherein the contacting step includes contacting the single terminal with the probe group consisting of four probes, and wherein the determining step includes utilizing a 4-Wire Ohm's Measurement to determine at least a portion of each of the plurality of path resistances.